



SEMiX® 5

3-Level NPC IGBT-Module

SEMiX155MLI07E4

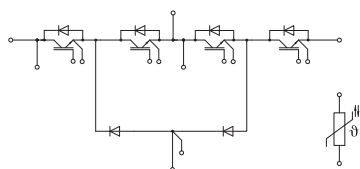
Target Data

Features

- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

Remarks*

- Case temperature limited to $T_C=125^\circ\text{C}$ max
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
- IGBT1 : outer IGBTs T1 & T4
- IGBT2 : inner IGBTs T2 & T3
- Diode1 : outer diodes D1 & D4
- Diode2 : inner diodes D2 & D3
- Diode5 : clamping diodes D5 & D6
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



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Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
IGBT1			
V_{CES}	$T_j = 25^\circ\text{C}$	650	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	187
		$T_c = 80^\circ\text{C}$	141
I_{Cnom}		150	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	450	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 360\text{ V}, V_{GE} \leq 15\text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 650\text{ V}$	10	μs
T_j		-40 ... 175	$^\circ\text{C}$
IGBT2			
V_{CES}	$T_j = 25^\circ\text{C}$	650	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	187
		$T_c = 80^\circ\text{C}$	141
I_{Cnom}		150	A
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V_{GES}		-20 ... 20	V
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T_j		-40 ... 175	$^\circ\text{C}$
Diode1			
V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	145
		$T_c = 80^\circ\text{C}$	107
I_{Fnom}		100	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	200	A
I_{FSM}	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	820	A
T_j		-40 ... 175	$^\circ\text{C}$
Diode2			
V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	145
		$T_c = 80^\circ\text{C}$	107
I_{Fnom}		100	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	200	A
I_{FSM}	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	820	A
T_j		-40 ... 175	$^\circ\text{C}$
Diode5			
V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	145
		$T_c = 80^\circ\text{C}$	107
I_{Fnom}		100	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	200	A
I_{FSM}	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	820	A
T_j		-40 ... 175	$^\circ\text{C}$
Module			
$I_t(\text{RMS})$		300	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V



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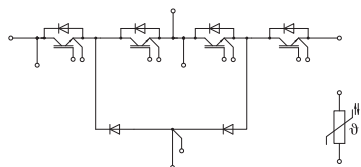
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Features

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- UL recognized file no. E63532
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Remarks*

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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT1						
$V_{CE(sat)}$	$I_C = 150\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		1.55	1.95	V
		$T_j = 150^\circ\text{C}$		1.75	2.15	V
V_{CE0}	chipllevel	$T_j = 25^\circ\text{C}$		0.90	1.00	V
		$T_j = 150^\circ\text{C}$		0.82	0.90	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		4.3	6.3	m Ω
		$T_j = 150^\circ\text{C}$		6.2	8.3	m Ω
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 4\text{ mA}$		5.1	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$				-	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		9.2		nF
C_{oes}		$f = 1\text{ MHz}$		0.58		nF
C_{res}		$f = 1\text{ MHz}$		0.27		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$			1200		nC
R_{Gint}	$T_j = 25^\circ\text{C}$			2.0		Ω
$t_{d(on)}$	$I_C = 100\text{ A}$ $V_{GE} = +15/-15\text{ V}$					ns
t_r						ns
E_{on}				1		mJ
$t_{d(off)}$						ns
t_f						ns
E_{off}				6		mJ
$R_{th(j-c)}$	per IGBT				0.32	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$)			0.07		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			TBD		K/W
IGBT2						
$V_{CE(sat)}$	$I_C = 150\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		1.55	1.95	V
		$T_j = 150^\circ\text{C}$		1.75	2.15	V
V_{CE0}	chipllevel	$T_j = 25^\circ\text{C}$		0.90	1.00	V
		$T_j = 150^\circ\text{C}$		0.82	0.90	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		4.3	6.3	m Ω
		$T_j = 150^\circ\text{C}$		6.2	8.3	m Ω
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 4\text{ mA}$		5.1	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$				-	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		9.2		nF
C_{oes}		$f = 1\text{ MHz}$		0.58		nF
C_{res}		$f = 1\text{ MHz}$		0.27		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$			1200		nC
R_{Gint}	$T_j = 25^\circ\text{C}$			2.0		Ω
$t_{d(on)}$	$I_C = 100\text{ A}$ $V_{GE} = +15/-15\text{ V}$					ns
t_r						ns
E_{on}				1		mJ
$t_{d(off)}$						ns
t_f						ns
E_{off}				6		mJ
$R_{th(j-c)}$	per IGBT				0.32	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$)			0.07		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material			TBD		K/W



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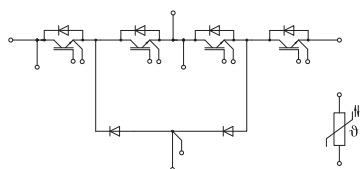
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- UL recognized file no. E63532
- NTC temperature sensor inside

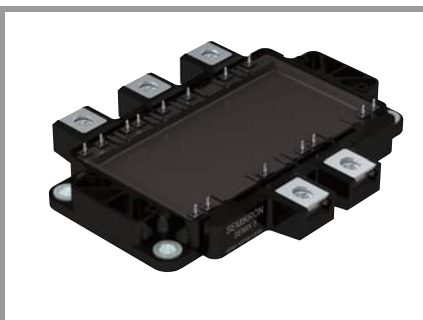
Remarks*

- Case temperature limited to $T_C=125^\circ\text{C}$ max
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
- IGBT1 : outer IGBTs T1 & T4
- IGBT2 : inner IGBTs T2 & T3
- Diode1 : outer diodes D1 & D4
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- Diode5 : clamping diodes D5 & D6
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Diode1						
$V_F = V_{EC}$	$I_F = 100\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$		1.40	1.76	V
		$T_j = 150^\circ\text{C}$		1.38	1.77	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$		1.04	1.24	V
		$T_j = 150^\circ\text{C}$		0.85	0.99	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$		3.6	5.3	mΩ
		$T_j = 150^\circ\text{C}$		5.3	7.8	mΩ
I_{RRM}	$I_F = 100\text{ A}$			-		A
Q_{rr}				-		μC
E_{rr}	$V_{GE} = +15/-15\text{ V}$			2.25		mJ
$R_{th(j-c)}$	per diode				0.51	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$)			0.12		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			TBD		K/W
Diode2						
$V_F = V_{EC}$	$I_F = 100\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$		1.40	1.76	V
		$T_j = 150^\circ\text{C}$		1.38	1.77	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$		1.04	1.24	V
		$T_j = 150^\circ\text{C}$		0.85	0.99	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$		3.6	5.3	mΩ
		$T_j = 150^\circ\text{C}$		5.3	7.8	mΩ
I_{RRM}	$I_F = 100\text{ A}$					A
Q_{rr}						μC
E_{rr}	$V_{GE} = +15/-15\text{ V}$			-		mJ
$R_{th(j-c)}$	per diode				0.51	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$)			0.12		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			TBD		K/W
Diode5						
$V_F = V_{EC}$	$I_F = 100\text{ A}$ chipelevel	$T_j = 25^\circ\text{C}$		1.40	1.76	V
		$T_j = 150^\circ\text{C}$		1.38	1.77	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$		1.04	1.24	V
		$T_j = 150^\circ\text{C}$		0.85	0.99	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$		3.6	5.3	mΩ
		$T_j = 150^\circ\text{C}$		5.3	7.8	mΩ
I_{RRM}	$I_F = 100\text{ A}$					A
Q_{rr}						μC
E_{rr}	$V_{GE} = +15/-15\text{ V}$			3		mJ
$R_{th(j-c)}$	per diode				0.51	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W}/(\text{m}^*\text{K})$)			0.12		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material			TBD		K/W



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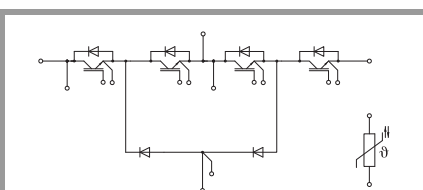
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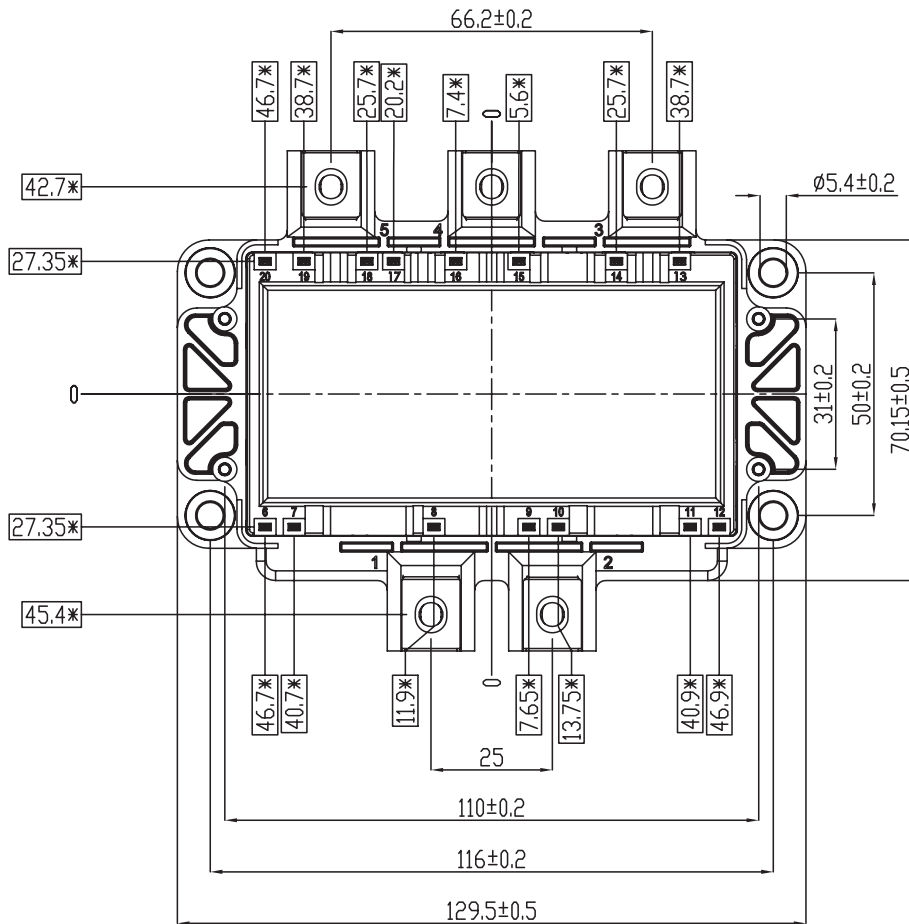
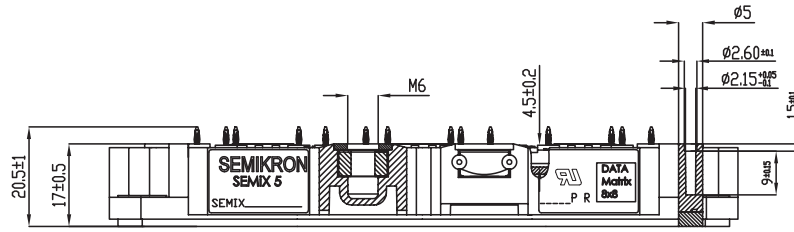
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Module						
L_{sCE1}				32		nH
L_{sCE2}				t.b.d.		nH
$R_{CC'+EE'}$	measured between terminal 5 and 1	$T_C = 25^\circ\text{C}$		1.2		m Ω
		$T_C = 125^\circ\text{C}$		1.65		m Ω
$R_{th(c-s)1}$	calculated without thermal coupling			0.009		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W/(m}^2\text{K)}$)			t.b.d.		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material			t.b.d.		K/W
M_s	to heat sink (M5)		3		6	Nm
M_t		to terminals (M6)	3		6	Nm
						Nm
W				398		g
Temperature Sensor						
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$;			$3550 \pm 2\%$		K



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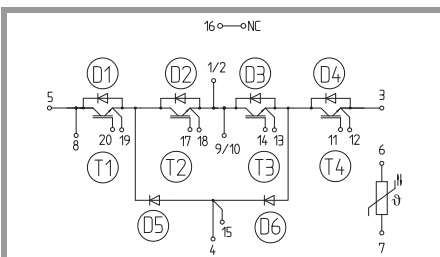
SEMiX155MLI07E4



* = All dimension with tolerance of $\begin{matrix} \oplus \\ \ominus \end{matrix} \ 0.4$

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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